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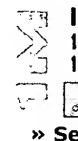
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Seungkyoon Woo; Myoung Ho Kim; Yoon Joon Lee;

Database Engineering and Applications Symposium, 1997. IDEAS '97. Proceedings., International , 25-27 Aug. 1997

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2 Log-driven backups: A recovery scheme for large memory database systems
Levy, E.; Silberschatz, A.;

Information Technology, 1990. 'Next Decade in Information Technology', Proceedings of the 5th Jerusalem Conference on (Cat. No.90TH0326-9) , 22-2 Oct. 1990

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3 Log-structured file systems
Douglis, F.; Ousterhout, J.;

 COMPCON Spring '89. Thirty-Fourth IEEE Computer Society International Conference: Intellectual Leverage, Digest of Papers. , 27 Feb.-3 March 1989
 Pages:124 - 129

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4 Cleaning up the clutter: why web standards matter [Web design]
Macmichael, R.A.;

IT Professional , Volume: 6 , Issue: 2 , March-April 2004

Pages:62 - 63

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5 Flicker correction for archived film sequences using a nonlinear model
Vlachos, T.;

Circuits and Systems for Video Technology, IEEE Transactions on , Volume:
14 , Issue: 4 , April 2004
Pages:508 - 516

[\[Abstract\]](#) [\[PDF Full-Text \(472 KB\)\]](#) IEEE JNL

6 Failure handling in an optimized two-safe approach to maintaining primary-backup systems

Kexiang Hu; Mehrotra, S.; Kaplan, S.;

Reliable Distributed Systems, 1998. Proceedings. Seventeenth IEEE Symposium on , 20-23 Oct. 1998
Pages:161 - 167

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7 Two-step backup mechanism for real-time main memory database recovery

Mi-Seon Choi; Hye-Sook Yoon; Eun-Mi Song; Young-Keol Kim; Young-Kuk Kim; Soong-Il Jin; Mi-Kyong Han; Wan Choi;

Real-Time Computing Systems and Applications, 2000. Proceedings. Seventh International Conference on , 12-14 Dec. 2000
Pages:453 - 457

[\[Abstract\]](#) [\[PDF Full-Text \(468 KB\)\]](#) IEEE CNF

8 Using software logging to support multiversion buffering in thread-level speculation

Garzaran, M.J.; Prvulovic, M.; Vinals, V.; Llabet, J.M.; Rauchwerger, L.; Tori J.;

Parallel Architectures and Compilation Techniques, 2003. PACT 2003. Proceedings. 12th International Conference on , 27 Sept.-1 Oct. 2003
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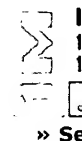
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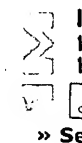
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